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U.S. PATENT DOCUMENTS								
EXAMINER INITIAL	l	DOCUMENT NUMBER	DATE	NAM	1E	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
50	AA	5,374,372	12/20/1994	Broze, et al.				
50	AB	5,444,096	08/22/1995	McCrea, et al.				
60	AC	5,837,223	11/17/1998	Barone, et al.				
32	AD	5,849,275	12/15/1998	Calello, et al.				
ζ ΑΕ 5,945,092		5,945,092	08/31/1999	Krog, et al.				
500	AF	5,945,095	08/31/1999	Mougin, et al.		 		
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30	AO	EP 0 620 270	10/19/1994	EPO EPO		×		
	AP	EP 0 829 254	03/18/1998	EPO			X	
	AQ	FR 2 789 010	10/01/1993	France (English Abstract Provided)			X	
	AR	JP 6-1158913	07/18/1986	Japan (English Abstract Provided)				X
	AS	JP 8-109121	04/30/1996	Japan (English Abstract Provided)				X
	AT	WO 9722328	06/26/1997	WIPO			X	
200	AU	WO 9943297	09/02/1999	WIPO			· x	
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
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*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								